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Komunikacijski kabli - Specifikacije za preskusne metode - 1-11. del: Električne preskusne metode - Karakteristična impedanca, vhodna impedanca, povratne izgube

Communication cables - Specifications for test methods - Part 1-11: Electrical test methods - Characteristic impedance, input impedance, return loss

Kommunikationskabel - Spezifikationen für Prüfverfahren - Teil 1-11: Elektrische Prüfverfahren - Wellenwiderstand, Eingangsimpedanz, Rückflußdämpfung

Câbles de communication - Spécifications des méthodes d'essai - Partie 1-11: Méthodes d'essais électriques - Impédance caractéristique, impédance d'entrée, affaiblissement de réflexion

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Eingangsimpedanz, Rückflußdämpfung

This draft European Standard is submitted to CENELEC members for enquiry.
Deadline for CENELEC: 2016-07-29.

It has been drawn up by CLC/TC 46X.

If this draft becomes a European Standard, CENELEC members are bound to comply with the CEN/CENELEC Internal Regulations which stipulate the conditions for giving this European Standard the status of a national standard without any alteration.

This draft European Standard was established by CENELEC in three official versions (English, French, German).
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44 **European foreword**

45 This document [prEN 50289-1-11:2016] has been prepared by CLC/TC 46X "Communication cables".

46 This document is currently submitted to the Enquiry.

47 The following dates are proposed:

- latest date by which the existence of this document has to be announced at national level (doa) dor + 6 months
- latest date by which this document has to be implemented at national level by publication of an identical national standard or by endorsement (dop) dor + 12 months
- latest date by which the national standards conflicting with this document have to be withdrawn (dow) dor + 36 months (to be confirmed or modified when voting)

48 This document will supersede EN 50289-1-11:2001.

49 This European Standard has been prepared under the European Mandate M/212 given to CENELEC by the
50 European Commission and the European Free Trade Association.

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51 1 Scope

52 This Part of EN 50289 details the test methods to determine characteristic impedance, input impedance and
53 return loss of cables used in analogue and digital communication systems.

54 It is to be read in conjunction with EN 50289-1-1, which contains essential provisions for its application.

55 2 Normative references

56 The following documents, in whole or in part, are normatively referenced in this document and are
57 indispensable for its application. For dated references, only the edition cited applies. For undated references,
58 the latest edition of the referenced document (including any amendments) applies.

59 EN 50289-1-1:2001, *Communication cables - Specifications for test methods - Part 1-1: Electrical test*
60 *methods - General requirements*

61 EN 50289-1-5:2001, *Communication cables - Specifications for test methods - Part 1-5: Electrical test*
62 *methods - Capacitance*

63 EN 50289-1-7:2001, *Communication cables - Specifications for test methods - Part 1-7: Electrical test*
64 *methods - Velocity of propagation*

65 EN 50290-1-2, *Communication cables - Part 1-2: Definitions*

66 3 Terms and definitions

67 For the purposes of this document, the terms and definitions given in EN 50290-1-2 and the following apply.

68 3.1 69 characteristic impedance

70 Z_c
71 (wave) impedance at the input of a homogeneous line of infinite length. The characteristic impedance Z_c of a
72 cable is defined as the quotient of a voltage and current wave which are propagating in the same direction,
73 either forwards or backwards.

$$74 \quad Z_c = \frac{u_f}{i_f} = \frac{u_r}{i_r} \quad (1)$$

75 where

Z_c is characteristic impedance;

$u_{f,r}$ is voltage wave propagating in forward respectively reverse direction;

$i_{f,r}$ is current wave propagating in forward respectively reverse direction.

76 3.2 77 mean characteristic impedance

78 Z_{cm}
79 in practice for real cables which always have structural variations the characteristic impedance is described
80 by the mean characteristic impedance which is derived from the measurement of the velocity of propagation
81 (EN 50289-1-7) and the mutual capacitance (EN 50289-1-5). However, this method is only applicable for
82 frequencies above 1 MHz and non-polar insulation materials (i.e. materials having a dielectric permittivity
83 which doesn't change over frequency). The mean characteristic impedance approaches at sufficiently high
84 frequencies (≈ 100 MHz) an asymptotic value Z_∞

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85 The characteristic impedance may be expressed as the propagation coefficient divided by the shunt
86 admittance. This relationship holds at any frequency.

$$87 \quad Z_c = \frac{\alpha + j\beta}{j\omega C(1 - j \tan \delta)} \approx \frac{\beta}{\omega C} - j \frac{\alpha}{\omega C} \quad (2)$$

88 where

Z_c is complex characteristic impedance (Ω);

α is attenuation coefficient (Np/m) ;

β is phase constant (rad/m);

$\tan \delta$ is loss factor;

ω is circular frequency (s^{-1});

C is mutual capacitance (F/m).

89 At high frequencies, where the imaginary component of impedance is small, and the real component and
90 magnitude are substantially the same we get for the mean characteristic impedance

$$91 \quad Z_{cm} \approx \frac{\beta}{\omega \times C} = \frac{\tau_p}{C} = \frac{1}{v \times C} \quad (3)$$

92 Where

Z_{cm} is mean characteristic impedance (m);

v is velocity of propagation (m/s);

τ_p is phase delay (s/m);

C is mutual capacitance (F/m).

93 3.3

94 terminated input impedance

95 Z_{in}

96 impedance measured at the near end (input) when the far end is terminated by a load resistance of value
97 equal to the system nominal impedance Z_R

98 3.4

99 open/short input impedance

100 Z_{os}

101 impedance measured at the near end (input) when the far end is terminated with its own impedance. In
102 practice this is the case when the round trip attenuation is greater than 40 dB at any measured frequency.
103 This property takes into account structural variations in the cable. For samples with lower round trip loss it is
104 determined by the open/short circuit method:

$$105 \quad Z_{os} = \sqrt{Z_{open} \times Z_{short}} \quad (4)$$

106 where

Z_{os} is input Impedance of the cable obtained from an open/short measurement;

Z_{open} is impedance with an open circuit at the far end of the cable;

Z_{short} is impedance with a short circuit at the far end of the cable.

107 3.5

108 fitted characteristic impedance

109 Z_{fit}

110 is obtained from a least square error function fitting of the open/short input impedance. The fitting can be
 111 applied on the magnitude, real and imaginary part of the input impedance. The fitted characteristic
 112 impedance is an alternative to the mean characteristic impedance to describe the characteristic impedance. It
 113 is only valid if the variations with frequency of the input impedance around its characteristic impedance are
 114 balanced.

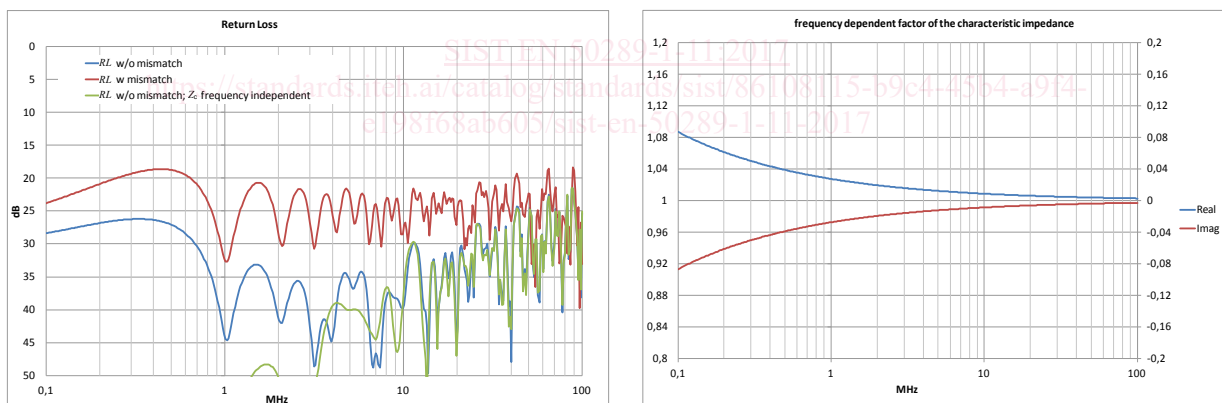
115 3.6

116 (operational) return loss

117 RL

118 (operational) return loss is measured at the near end (input) when the far end is terminated by a load
 119 resistance of value equal to the system nominal impedance Z_R . It quantifies the reflected signal caused by
 120 impedance variations. The (operational) return loss takes into account the structural variations along the
 121 cable length and the mismatch between the reference impedance and the (mean) characteristic impedance
 122 of the cable (pair). If the (mean) characteristic impedance of the cable (pair) is different from the reference
 123 impedance, one gets, especially at lower frequencies (where the round trip attenuation is low), multiple
 124 reflections that are overlaid to the structural and junction reflections. Therefore, return loss RL is also
 125 referenced as operational return loss.

126 As an example, Figure 1, shows the operational return loss under different conditions. The blue line shows
 127 the return loss of a pair having a characteristic impedance equal to the reference impedance but taking into
 128 account that the impedance is varying with frequency (see right-hand graph). The red line shows the return
 129 loss of a pair having a characteristic impedance that is different from the reference impedance (110 Ω vs. 100
 130 Ω). For both lines, periodic variations – that are caused by multiple reflections between the junctions at the
 131 near and far end – are observed. The green line shows a simulation of a pair having a frequency independent
 132 characteristic impedance which is equal to the reference impedance.



133 **Figure 1 — Return loss with and without junction reflections**

134 3.7

135 open/short return loss

136 $OSRL$

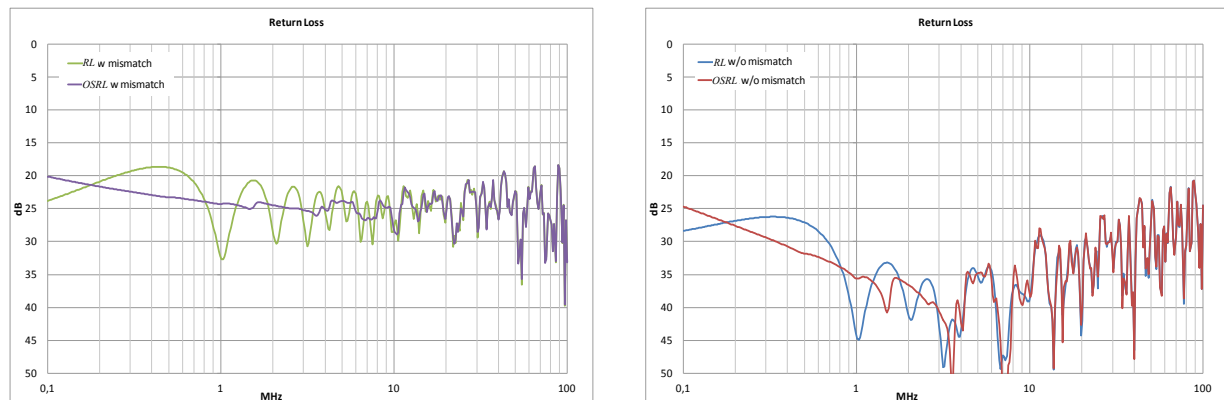
137 way to avoid in the measurement of return loss multiple reflections due to a mismatch between the
 138 characteristic impedance (asymptotic value at high frequencies) of the CUT and the reference impedance is
 139 to use a CUT terminated in its nominal impedance and having a very long test length such that the round trip
 140 attenuation of the CUT is at least 40 dB at the lowest frequency to be measured. For standard LAN cables,
 141 this would result in a CUT length of roughly 1 000 m for the lowest frequency of 1 MHz.

142 Another way (when long CUT length is not available) is to measure the characteristic impedance (open/short
 143 method) and to calculate the return loss. As the characteristic impedance is obtained from the measurement
 144 of the open and short circuit impedance, it is proposed to name such obtained return loss open/short return
 145 loss.

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146 This open/short return loss includes the effect of structural variations and the mismatch at the near end
 147 (including the effect due to a frequency-dependent characteristic impedance), but it does not take into
 148 account multiple reflections.

149 Figure 2 shows the difference between operational return loss and open/short return loss. The left-hand
 150 graph shows the results of a pair having a characteristic impedance which is different from the reference
 151 impedance (110 Ω vs. 100 Ω). The right-hand graph shows the results of a pair having a characteristic
 152 impedance which is equal to the reference impedance (100 Ω). One may recognize that the open/short return
 153 loss does not take into account multiple reflections.



154 **Figure 2 — Return loss and open/short return loss**

154

155 3.8 structural return loss

156 *SRL*

157 The structural return loss is the return loss where only structural variations along the cable are taken into
 158 account. The mismatch effects at the input and output of the transmission line (including the effect due to a
 159 frequency-dependent characteristic impedance) have been eliminated. The structural return loss cannot be
 160 measured directly but is calculated from the measurement of the characteristic impedance (open/short
 161 method).
 162

$$163 \quad SRL = 20 \times \lg \left| \frac{Z_{OS} - Z_{fit}}{Z_{OS} + Z_{fit}} \right| \quad (5)$$

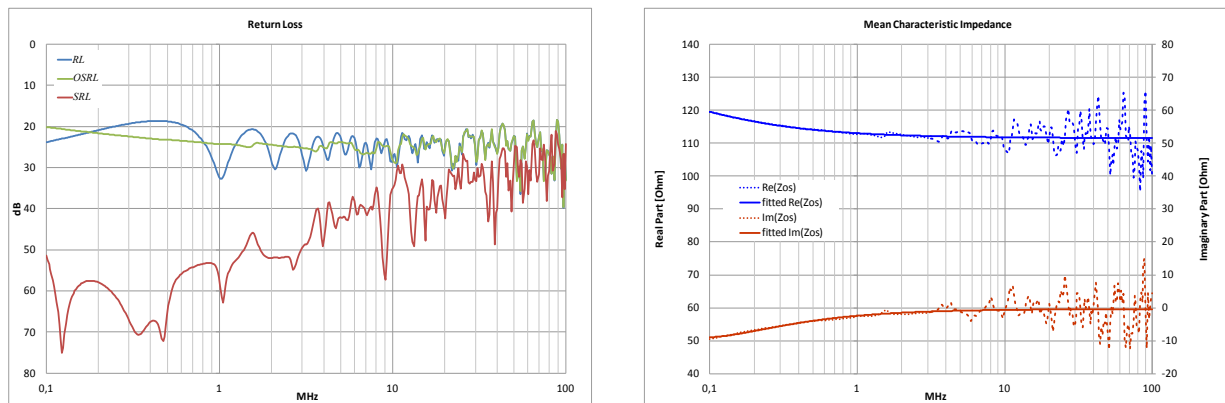
164 where

Z_{OS} is the (complex) input impedance obtained from the measurement of the open and short circuit impedance;

Z_{fit} is the (complex) characteristic impedance obtained from a curve fitting of the real and imaginary part of Z_{OS} .

165 The left-hand graph of Figure 3 shows the operational return loss, open/short return loss and structural return
 166 loss of a CUT having a characteristic impedance of 110 Ω. A difference between both is observable. The
 167 operational return loss takes into account all effects (structural variations, mismatch effects at the input and
 168 output). The open/short return loss does not take into account mismatch effects at the output (i.e. no multiple
 169 reflections). Whereas the structural return loss only takes into account structural variations along the cable.

170 The right-hand graph shows the real and imaginary part of the mean characteristic impedance (obtained from
 171 the measurement of the open and short circuit impedance) and its fitting.



172 **Figure 3 — Return loss, open short return loss and structural return loss**

173 **3.9**
174 **parasitic inductance corrected return loss**

175 **PRL**

176 return loss where the effect a parasitic inductance (due to sample preparation and/or test fixture), which is
177 observed as an increase of the input impedance at high frequencies (above 100 MHz), has been corrected

178 **3.10**
179 **gated return loss**

180 **GRL**

181 return loss where the effect of the test fixtures and sample preparation, which is observed as an increase of
182 the input impedance at high frequencies (above 100 MHz), has been corrected by a gating function

183 **3.11**
184 **fitted return loss**

185 **FRL**

186 return loss where the effect of the test fixtures and sample preparation, which is observed as an increase of
187 the input impedance at high frequencies (above 100 MHz), has been corrected by applying fitting function on
188 the input impedance

189 **4 Test method for mean characteristic impedance (S₂₁ type measurement)**

190 **4.1 Principle**

191 This method shall only be applied for cables having non-polar insulation materials (e.g. PE, PTFE), i.e.
192 materials having a dielectric permittivity which doesn't change over frequency. Or in other words this method
193 shall only be applied to cables having a mutual capacitance which doesn't change over frequency.

194 The mean characteristic impedance shall be derived from the measurement of the velocity of propagation,
195 respectively phase delay, according to EN 50289-1-7 and the mutual capacitance according EN 50289-1-5.
196 The measurement shall be carried out at frequencies above 100 MHz where the phase delay approaches an
197 asymptotic value.

198 **4.2 Expression of test results**

199 The mean characteristic impedance Z_{cm} shall be derived from Formula (6):

200
$$Z_{cm} = \frac{\tau_p}{C} = \frac{1}{v \times C} \quad (6)$$

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201 where

- Z_{cm} is mean characteristic impedance (m);
- v is velocity of propagation (m/s), measured according EN 50289-1-7;
- τ_p is phase delay (s/m), measured according EN 50289-1-7;
- C is mutual capacitance (F/m), measured according EN 50289-1-5.

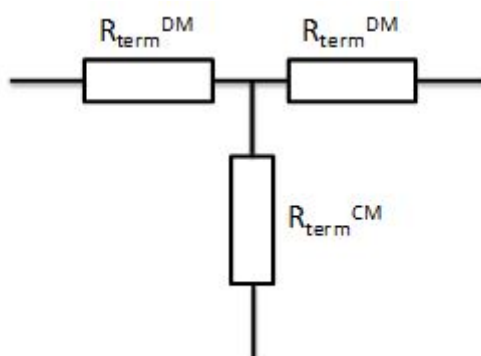
202 5 Test method for input impedance and return loss (S_{11} type measurement)

203 5.1 Method A: measurement of balanced cables using balun setup

204 5.1.1 Test Equipment

205 The test equipment consists of a 2-port vector network analyser (VNA) with:

- 206 — S-parameter set-up;
- 207 — Balun to convert the unbalanced signal of the VNA to a balanced signal. The balun shall have an
208 impedance on the primary (unbalanced) side equal to the nominal impedance of the measuring devices
209 (in general 50 Ω) and on the secondary (balanced) side equal to the nominal impedance of the CUT (e.g.
210 100 Ω) (the balun shall fulfil the requirements of Class A baluns as described in EN 50289-1-1);
- 211 — To perform a calibration of the test equipment (on the secondary side of the balun), a short circuit, an
212 open circuit and a reference load are required. The short circuit shall have negligible inductance and the
213 open circuit shall have negligible capacitance. The load resistor shall have a value close (within 1%) to
214 the nominal impedance of the CUT (e.g. 100 Ω) and with negligible inductance and capacitance;
- 215 — For the measurement of the input impedance and (operational) return loss a T-resistor network (see
216 Figure 4) is required to terminate the common and differential mode impedance at the far end of the
217 sample. The differential mode termination resistors shall be matched in pairs, each half the value of the
218 differential mode reference impedance Z_R (in general 100 Ω). If not specified otherwise, for example by
219 particular cabling standards, the common mode termination resistors shall be:
 - 220 — 0 Ω for individually screened pair cables;
 - 221 — 25 Ω for overall screened cables;
 - 222 — 45 Ω to 50 Ω for unscreened cables.



223

224 Key

- R_{term}^{DM} differential mode termination resistor
- R_{term}^{CM} common mode termination resistor

225

Figure 4 — T-resistor network